


Search Notes 	Application/Control No. 10574286	Applicant(s)/Patent Under Reexamination OIKAWA ET AL.
	Examiner CEDRIC CHAN	Art Unit 1773

SEARCHED			
Class	Subclass	Date	Examiner
422	99,102,104,255,261,266,292	12/16/2010	CC
134	73,75,82,83,85,92,104.1,117,165	12/16/2010	CC
216	83,84,100,8,10	12/16/2010	CC
118	400,404,421,427	12/16/2010	CC
422	500,547,566,300,301	3/20/2011	CC

SEARCH NOTES		
Search Notes	Date	Examiner
inventor name search (PALM)	2/5/2010	CC
inventor name search (EAST)	2/13/2010	CC
searched US/Foreign databases -- EAST/USPat,OCR,PGPub,EPO,JPO,Derwent	2/13/2010	CC
assignee search (EAST)	8/21/2010	CC
updated class, inventor search & updated keyword search of US/For databases (see EAST History)	8/21/2010	CC
updated inventor/assignee search w/ lim text in EAST; updated keyword search	12/16/2010	CC
updated classification search, additionally searched new subclasses in class 134 and 118	12/16/2010	CC
Interference search (see EAST Search History, attached)	12/16/2010	CC
updated 422 class search	3/20/2011	CC
updated class, inventor, assignee search & expanded keyword search	5/10/2011	CC
interference search	5/10/2011	CC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
422	500,292,300,301	5/10/2011	CC
134	104.1,117	5/10/2011	CC
118	404,421	5/10/2011	CC

/C. C./ Examiner.Art Unit 1773	
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